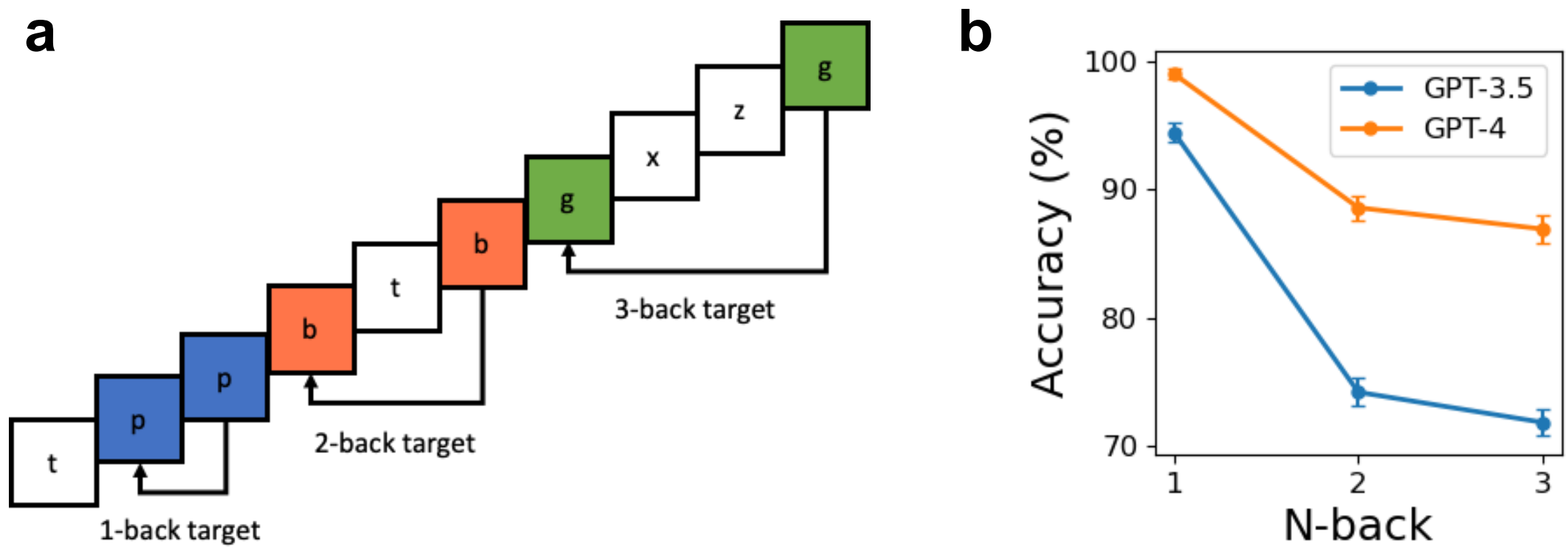


Self-Attention Limits Working Memory Capacity of Transformer-Based Models

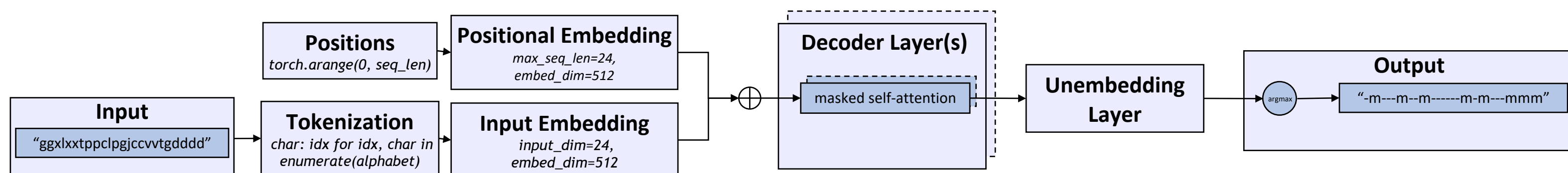
Dongyu Gong, Yale University (dongyu.gong@yale.edu); Hantao Zhang, Yale University

Background

Transformer-based large language models (LLMs) has striking limits in their working memory capacity, as measured by N-back tasks in cognitive science [1]. However, there is still a lack of mechanistic interpretability as to why this phenomenon would arise.

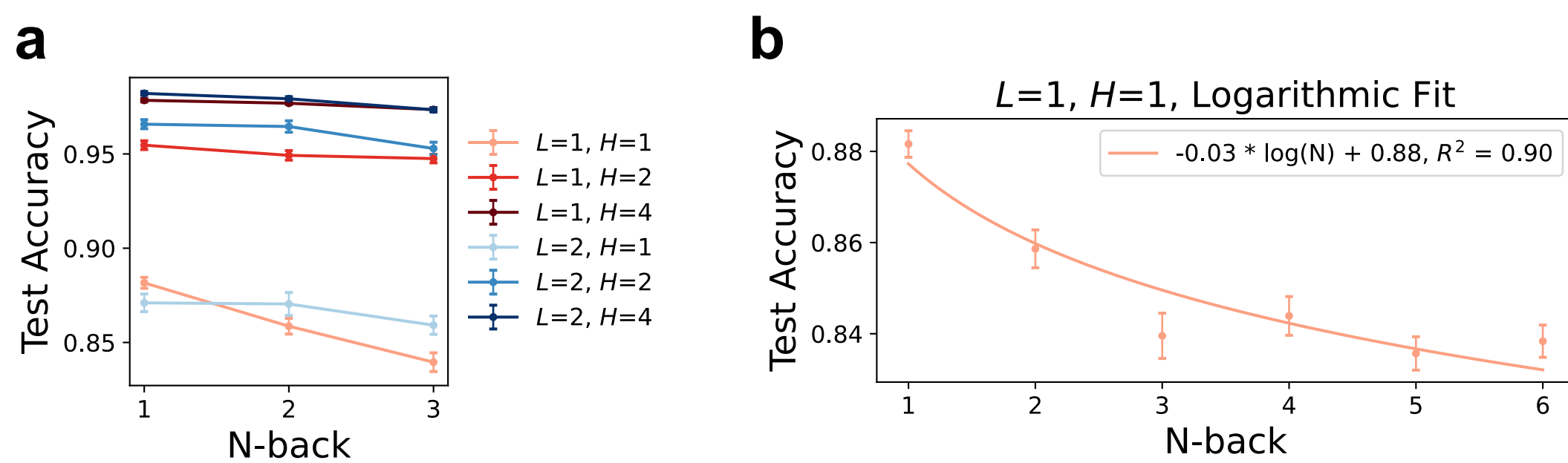


Methods



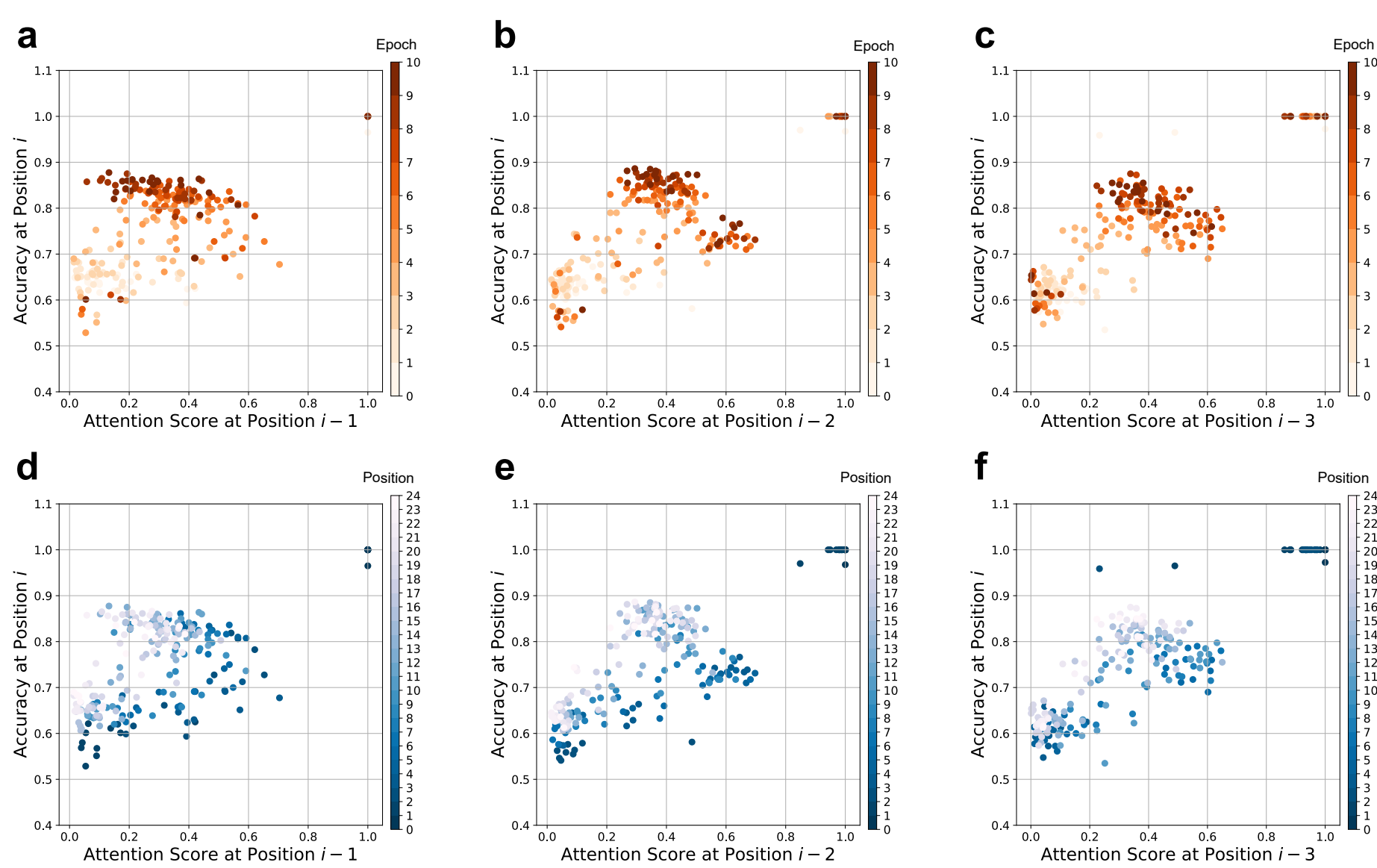
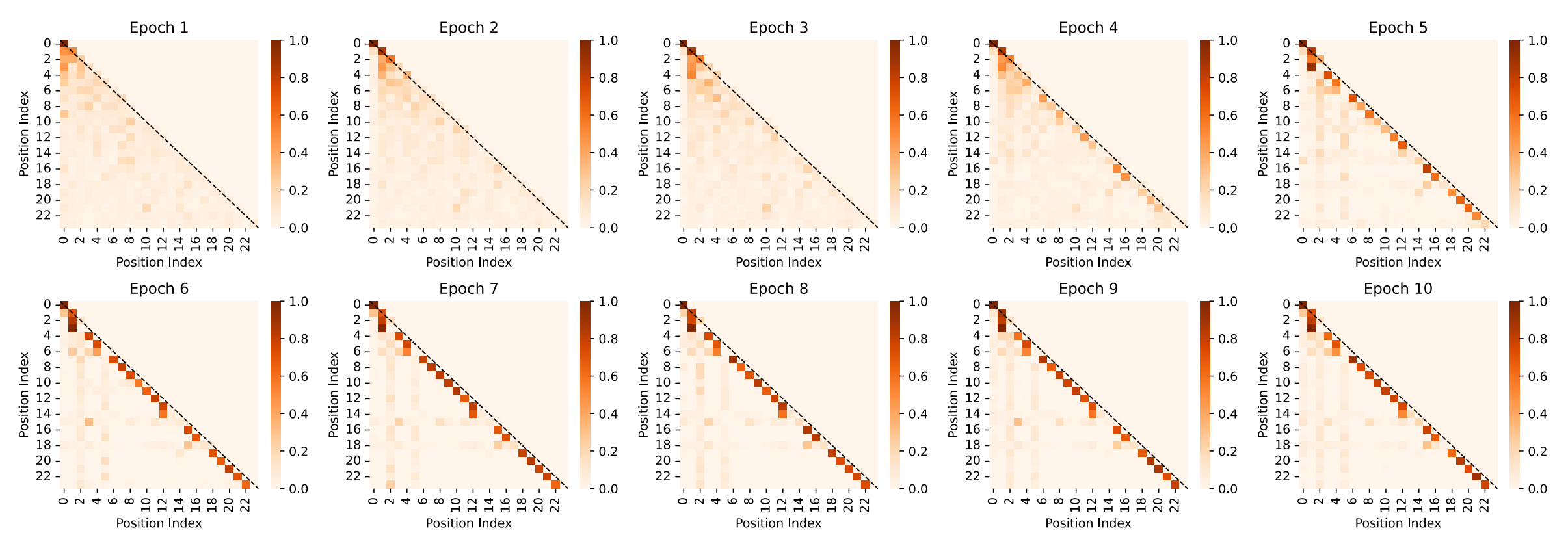
Inspired by the **executive attention theory** in cognitive science, we hypothesize that the self-attention mechanism within Transformer-based models might be responsible for their working memory capacity limits. To test this hypothesis, we train vanilla decoder-only transformers to perform N-back tasks. We mainly focus our analysis on a causal Transformer containing one decoder layer with only one attention, although we also test a few architectural variants in the number of decoder layers (L) and number of attention heads per layer (H) for comparisons.

Results



1. Model accuracy decreases as N increases. We find a significant decline in model performance as N increases for the 1-layer 1-head model. To further confirm this pattern, we extend the task to $N = 6$ and find a significant logarithmic decline in the test accuracy as N increases.

2. Attention scores during training reflect the trajectory of learning. Starting with almost uniformly distributed attention scores in each row, attention scores gradually aggregate to a line corresponding to the N-back positions.



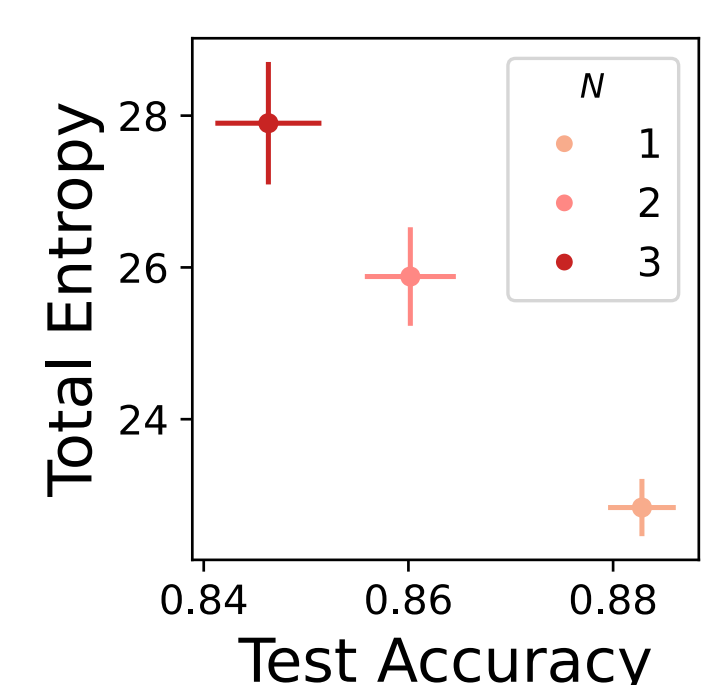
3. Attention score at position $i - N$ increases with test accuracy at position i . Over training epochs, the attention score at position $i - N$ increases along with the accuracy at position i (panel a-c). When using the same data but assigning colors to the dots according to which position each dot belongs to (panel d-f), there is a clear pattern that attention scores get dispersed at later locations.

4. Total entropy of attention scores increases as N increases. We define the total entropy H_N of each attention score matrix $A \in \mathbb{R}^{24 \times 24}$ as

$$H_N(A) = - \sum_{i=1}^{24} \sum_{j=1}^{24} A_{i,j} \log(A_{i,j})$$

where

$$A_{i,j} = \text{Softmax}\left(\frac{QK^T}{\sqrt{d_k}}\right)_{i,j}$$



We find that H_N increases as N increases, leading to the decrease in test accuracy.

Discussion

Our findings suggest a shared role of attention in the working memory capacity of humans and LLMs. The mechanistic interpretability of working memory capacity limits in Transformer-based models could inform future efforts to design more powerful model architectures with enhanced cognitive capabilities [2].